## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination				
10599310	VOLOSHIN ET AL.				

VOLOSHIN ET AL.

Examiner

Art Unit

Young J Kim

1637

## **SEARCHED**

Class	Subclass	Date	Examiner

<b>SEARCH</b>	<b>NOTES</b>
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Search Notes	Date	Examiner
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) -	9/29/2010	/YJK/
see enclosed for text search strategy		
STN commercial Databases (Biosis, Medline, Embase, Embal, CAPlus) -	9/29/2010	/YJK/
see enclosed for text search strategy		
STN search updated - see enclosed	4/28/2011	/YJK/
Patent Databases - updated - see enclosed	4/28/2011	/YJK/
Patent Databases - udpated	10/6/2011	/YJK/

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	Interference Database search - see enclosed	10/6/2011	/YJK/

/Young J Kim/ Primary Examiner.Art Unit 1637

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